

Dedicated to the memory of Prof. M. Sheinkman effect of ultrasonic treatment on the defect structure of the Si-SiO₂ system

Kropman, Daniel; Dolgov, Sergei; Onufrijevs, Pavels; Dauksta, Edvins Gettering and Defect Engineering in Semiconductor Technology XV 2014 / p. 352-357 : ill <https://doi.org/10.4028/www.scientific.net/SSP.205-206.352> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Conference proceedings at WOS](#) [Article at WOS](#)